	Application/Control No.	Applicant(s)/Patent Under Reexamination
Issue Classification		TSENG, WAYNE
	Examiner	Art Unit
	Bae, Ji H	2115

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	ORIGINAL	INAL	NI N	ERNATIONAL	INTERNATIONAL CLASSIFICATION	7
	CLASS	SUBCLASS	CLAIMED	Q	NON-CI	NON-CLAIMED
713		503	G 0 6 F	1 / 04		
	CROSS REFERENCE(S)	ERENCE(S)	0 0 X	5 / 04		
CLASS	SUBCLASS (C	SUBCLASS (ONE SUBCLASS PER BLOCK)				
714	200					
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Ji H. Bae	XIBan 1-23-20				Total Clain	Total Claims Allowed:
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7	(1) 1/h	of the	1/31/07	707	O.G. Print Claim(s)	O.G. Print Figure
degal Instrame	egal Instruments Examiner) (Date)	(Primary Examiner)	(Date)	_	-	7

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